

This Page Is Inserted by IFW Operations
and is not a part of the Official Record

BEST AVAILABLE IMAGES

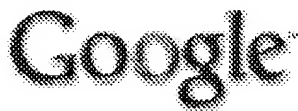
Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

IMAGES ARE BEST AVAILABLE COPY.

**As rescanning documents *will not* correct images,
please do not report the images to the
Image Problem Mailbox.**



[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [more »](#)

semiconductors simulation scanning s-pari

[Search](#)

[Advanced Search](#)
[Preferences](#)

"schools" (and any subsequent words) was ignored because we limit queries to 10 words.

Web Results 1 - 10 of about 13 for semiconductors simulation scanning s-parameters impedance "scanni

[PDF] Predicting performance straight from the wafer

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... the desired chip data, **simulation** programs can ... for various discrete GaAs **semiconductors** and SMX ... 450 transistor seen under the **scanning electron microscope** 30 25 ...

www.eetasia.com/ARTICLES/2000MAR/2000MAR30_RFD_WLP_AN.PDF - [Similar pages](#)

[PDF] MODELING AND SIMULATION OF HIGH SPEED INTERCONNECTS

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... include inter- connect modeling and **simulation**, analog and 47 4.9 **Scanning Electron Micrograph** of the cross ... Technol- ogy Roadmap for **Semiconductors** [1]. The ...

www4.ncsu.edu/~mbs/vitae_theses/biswas_ms_1998.pdf - [Similar pages](#)

2003-05 School of Engineering Graduate Catalog - - SMU

... metallization, as well as **scanning** electron microscopy ... the physically-based **simulation** model parameters ... recombination mechanisms in metals and **semiconductors**. ...

www.smu.edu/catalogs/graduate/engr/ee.asp - 88k - [Cached](#) - [Similar pages](#)

[PDF] Elect Engr LO

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... imaging (eg, laser **scanning**, microtomography), character ... of carrier transport in **semiconductors**, double-crystal X ... image processing, **data simulation** and analysis ...

www-ee.eng.buffalo.edu/news/department/PDF%20Files/electen.pdf - [Similar pages](#)

NUS: Department of Electrical & Computer Engineering

... **Scanning**, 18 (1996): 35-44. ... MK Haldar and FVC Mendis, Dynamic **simulation** of overmodulation ... International

Conference on the Physics of **Semiconductors**, April 1996 ...

www.ece.nus.edu.sg/research/statistics/publications/ee-1996.shtml - 101k - [Cached](#) - [Similar pages](#)

[PDF] RESEARCH ACTIVITIES IN MICROELECTRONICS 1998

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... Dr. Ari Lehto, Sensor Technology Dr. Pekka Kuivalainen, Modelling and **Simulation** of Electronic ... resistances can be seen as an improved output **impedance** fit of ...

www.vtt.fi/tte/research/tte6/pdf_files/mikres98.pdf - [Similar pages](#)

[PDF] Schottky Diode Integrated Circuits for Sub-Millimeter-Wave ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... 55 5.1 Quasi-static **simulation** of CPW with center conductor in air

... 70 5.15 Measured S 11 and S 22 of tapered **impedance** line ...

www.ece.ucsb.edu/Faculty/rodwell/Downloads/theses/Allen_thesis.pdf - [Similar pages](#)

[PDF] Near Speed-of-Light On-Chip Electrical Interconnects

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... for **Semiconductors** ... the **simulation**..... a

Scanning Electron Microscope (...

marco.stanford.edu/swong/Richard.pdf - [Similar pages](#)

Conference Papers

... United States: **Scanning** Microscopy International, 1995. ... Haldar and FVC Mendis, Dynamic **simulation** of overmodulation ... on the Physics of **Semiconductors**, April 1996 ...
www.ee.nus.edu.sg/research/conference.html - 101k - [Cached](#) - [Similar pages](#)

[\[PDF\] Annual Research Report Electrical Engineering 1999 Excerpt](#)

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... Using this model in a '**Simulation** and Design Environment' (SDA), a ... RAEL DSP Pipeline Arbiter (co-operation with Philips **Semiconductors**, Embedded Systems ...

www.ele.tue.nl/onderzoek/ozvers99.pdf - [Similar pages](#)

In order to show you the most relevant results, we have omitted some entries very similar to the 10 already displayed.

If you like, you can [repeat the search with the omitted results included](#).

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2004 Google

Dialog DataStar

[options](#)
[logout](#)
[feedback](#)
[help](#)
[databases](#)
[easy search](#)

Advanced Search: INSPEC - 1969 to date (INZZ)

[limit](#)

Search history:

No.	Database	Search term	Info added since	Results	
1	INZZ	Tsai-R\$	unrestricted	173	show titles
2	INZZ	1 AND semiconductor	unrestricted	28	show titles
3	INZZ	2 AND simulation	unrestricted	2	show titles


[hide](#) | [delete all search steps...](#) | [delete individual search steps...](#)
Enter your search term(s): [Search tips](#)
 [whole document](#)

 Information added since: or: [none](#)
 (YYYYMMDD)

[search](#)

Select special search terms from the following list(s):

- ☒ Classification codes A: Physics, 0-1
- ☒ Classification codes A: Physics, 2-3
- ☒ Classification codes A: Physics, 4-5
- ☒ Classification codes A: Physics, 6
- ☒ Classification codes A: Physics, 7
- ☒ Classification codes A: Physics, 8
- ☒ Classification codes A: Physics, 9
- ☒ Classification codes B: Electrical & Electronics, 0-5
- ☒ Classification codes B: Electrical & Electronics, 6-9
- ☒ Classification codes C: Computer & Control
- ☒ Classification codes D: Information Technology
- ☒ Classification codes E: Manufacturing & Production
- ☒ Treatment codes
- ☒ INSPEC sub-file
- ☒ Publication types

 Language of publication

[Top](#) - [News & FAQs](#) - [Dialog](#)

© **2004** Dialog

	Type	Hits	Search Text
22	BRS	0	(asynchronous adj buffer) and (((emulation adj processor) near plurality))
23	BRS	1	(asynchronous adj buffer) and emulation
24	BRS	0	asynchronous adj buffer adj card
25	BRS	16	(asynchronous adj buffer) and multiplex
26	BRS	0	(asynchronous adj buffer) and multiplex and emulation
27	BRS	3	(asynchronous adj buffer) and (multi-bit)
28	BRS	0	(asynchronous adj buffer) and (multi-bit) and emulation
29	BRS	0	emulation and (common near path) and multi-bit
30	BRS	267	emulation and multi-bit
31	BRS	2	emulation and multi-bit and multi-step
32	BRS	174	emulation and (digital adj logic)
33	BRS	0	emulation and (digital adj logic) and (common near path)
34	BRS	124	emulation and (digital adj logic) and path
35	BRS	26	emulation and (digital adj logic) and (multiple adj signals)
36	BRS	0	(emulation and (multiple adj signals)).ti.
37	BRS	12	(emulation and signals).ti.
38	BRS	0	(emulation and signals).ti. and (plurality near processors)
39	BRS	9	(emulation and signals).ti. and plurality
40	BRS	4	(emulation and signals).ti. and plurality and clock
41	BRS	1	(emulation and signals).ti. and plurality and clocks and path
42	BRS	4	(emulation and signals).ti. and plurality and clocks
43	BRS	0	(common and path).ti. and (digital adj logic)
44	BRS	70	(common and path).ti.
45	BRS	7732	(common and path).ti. emulation
46	BRS	0	(common and path).ti. and emulation
47	BRS	2	(emulation and signals).ti. and plurality and clocks and buffer
48	BRS	5	(asynchronous and emulation).ti.
49	BRS	5	(asynchronous and emulation).ti. and emulation
50	BRS	3	(asynchronous and emulation).ti. and emulation and circuit
51	BRS	3	(asynchronous and emulation).ti. and emulation and logic
52	BRS	0	(asynchronous and emulation and logic).ti.
53	BRS	11	asynchronous and (emulation and logic).ti.
54	BRS	38	(semiconductor and simulation).ti.

	DBs	Time Stamp	Comments	Error Definition
22	USPAT	2004/07/12 13:41		
23	USPAT	2004/07/12 13:41		
24	USPAT	2004/07/12 15:20		
25	USPAT	2004/07/12 13:43		
26	USPAT	2004/07/12 13:43		
27	USPAT	2004/07/12 13:48		
28	USPAT	2004/07/12 13:49		
29	USPAT	2004/07/12 13:49		
30	USPAT	2004/07/12 13:50		
31	USPAT	2004/07/12 13:50		
32	USPAT	2004/07/12 13:50		
33	USPAT	2004/07/12 13:51		
34	USPAT	2004/07/12 13:52		
35	USPAT	2004/07/12 13:53		
36	USPAT	2004/07/12 13:53		
37	USPAT	2004/07/12 13:55		
38	USPAT	2004/07/12 13:55		
39	USPAT	2004/07/12 13:57		
40	USPAT	2004/07/12 14:00		
41	USPAT	2004/07/12 14:00		
42	USPAT	2004/07/12 14:05		
43	USPAT	2004/07/12 14:02		
44	USPAT	2004/07/12 14:02		
45	USPAT	2004/07/12 14:02		
46	USPAT	2004/07/12 14:02		
47	USPAT	2004/07/12 14:05		
48	USPAT	2004/07/12 15:21		
49	USPAT	2004/07/12 15:25		
50	USPAT	2004/07/12 15:22		
51	USPAT	2004/07/12 15:22		
52	USPAT	2004/07/12 15:25		
53	USPAT	2004/07/12 15:25		
54	USPAT; IBM_TDB	2004/07/15 10:00		

	Type	Hits	Search Text
55	BRS	8	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)
56	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and scaling and bias and
57	BRS	8	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)
58	BRS	4	(semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)) and bias
59	BRS	0	(semiconductor and simulation).ti. and fabricating and measuring and testing
60	BRS	5	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying
61	BRS	4	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and equivalent
62	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor)
63	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and sample
64	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and source
65	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and FET
66	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and FET
67	BRS	0	FET and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying
68	BRS	73	FET and simulation and fabricating and measurin
69	BRS	24	FET and simulation and fabricating and measuring and testing

	Type	Hits	Search Text
70	BRS	4	FET and simulation and fabricating and measuring and testing and scaling
71	BRS	4	FET and simulation and fabricating and measuring and testing and scaling and bias
72	BRS	4	FET and simulation and fabricating and measuring and testing and scaling and bias and
73	BRS	3	MOSFET and simulation and fabricating and measuring and testing and scaling and bias and temperature

	Type	Hits	Search Text
1	BRS	21	FPGA and emulation and multiplexing and (logic adj analyzer)
2	BRS	3	FPGA and emulation and (logic adj analyzer) and (multiplexing near subsystem)
3	BRS	16	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem)
4	BRS	15	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem) and frequencies
5	BRS	6	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies
6	BRS	6	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and clock
7	BRS	4	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and clock and controller
8	BRS	3	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller
9	BRS	0	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (increase near frequencies) and clock and controller
10	BRS	3	(FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller) and tags
11	BRS	0	(FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller) and lables
12	BRS	0	(FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller) and
13	BRS	3	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and sampling
14	BRS	10	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and sampling
15	BRS	1	6556936.pn.
16	BRS	69	emulation near plurality
17	BRS	104	emulation adj processor
18	BRS	5	((emulation adj processor) near plurality)
19	BRS	0	((emulation adj processor) near plurality) and asynchronous
20	BRS	0	asynchronous adj buffer
21	BRS	63	asynchronous adj buffer